Notice of References Cited Application/Control No. 10/656,052 Examiner Elliot L Frank Applicant(s)/Patent Under Reexamination YEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0198619 A1	12-2002	Denton et al.	700/107
*	В	US-2003/0004595 A1	01-2003	Seimiya et al.	700/97
*	С	US-2004/0059650 A1	03-2004	Cruz et al.	705/028
*	D	US-5,307,261 A	04-1994	Maki et al.	705/29
*	Е	US-5,311,424 A	05-1994	Mukherjee et al.	705/29
*	F.	US-5,325,304 A	06-1994	Aoki, Toshiaki	700/100
*.	G	US-5,523,611 A	06-1996	Mischel et al.	257/461
*	Н	US-5,960,405 A	09-1999	Trefethan et al.	705/9
*	1	US-6,222,212 B1	04-2001	Lee et al.	257/207
*	J	US-6,352,880 B1	03-2002	Takai et al.	438/106
*	К	US-6,448,152 B1	09-2002	Henley et al.	438/458
*	L	US-6,463,345 B1	10-2002	Peachey-Kountz et al.	700/99
*	М	US-6,699,727 B1	03-2004	Toprac et al.	438/17

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		
	Р					
	Q					
	R			7420-040		V
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.